UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/540,785	06/27/2005	Atsushi Miyake	SUGI-102US	2095

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EXAMINER
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

-- *The MAILING DATE of this communication appears on the cover sheet with the correspondence address* --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE _3_ MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.
- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
  Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

1)☒ Responsive to communication(s) filed on _16 April 2008_.

2a)☐ This action is **FINAL**.   2b)☒ This action is non-final.

3)☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

4)☒ Claim(s) _1,2,4,5,7,8,10 and 11_ is/are pending in the application.

    4a) Of the above claim(s) _____ is/are withdrawn from consideration.

5)☐ Claim(s) _____ is/are allowed.

6)☒ Claim(s) _1,2,4,5,7,8,10 and 11_ is/are rejected.

7)☐ Claim(s) _____ is/are objected to.

8)☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

9)☐ The specification is objected to by the Examiner.

10)☐ The drawing(s) filed on _____ is/are: a)☐ accepted or b)☐ objected to by the Examiner.

    Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

    Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).

11)☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

12)☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).

    a)☐ All   b)☐ Some * c)☐ None of:

      1.☐ Certified copies of the priority documents have been received.

      2.☐ Certified copies of the priority documents have been received in Application No. _____.

      3.☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

    * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

1) ☐ Notice of References Cited (PTO-892)
2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3) ☐ Information Disclosure Statement(s) (PTO/SB/08)
    Paper No(s)/Mail Date _____.

4) ☐ Interview Summary (PTO-413)
    Paper No(s)/Mail Date. _____.
5) ☐ Notice of Informal Patent Application
6) ☐ Other: _____.

Detailed Action

Response to Arguments

Applicant's arguments with respect to claims 1, 2, 4, 5, 7, 8, 10, & 11 have been considered but are moot in view of the new ground(s) of rejection.

Claim Rejections - 35 USC § 103

1.   The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

> (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

The factual inquiries set forth in *Graham* **v.** *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

1.   Determining the scope and contents of the prior art.
2.   Ascertaining the differences between the prior art and the claims at issue.
3.   Resolving the level of ordinary skill in the pertinent art.
4.   Considering objective evidence present in the application indicating obviousness or nonobviousness.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was

not commonly owned at the time a later invention was made in order for the examiner to

consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g)

prior art under 35 U.S.C. 103(a).

2.   Claims 4, 5, 10, &11 are rejected under 35 U.S.C. 103(a) as being unpatentable

over **Pingel et al** (WO98/17993) (Pingel).

Regarding **Claims 4, 5, 10, &11**, Pingel discloses and shows in **figs. 1 & 2** an

estimating method of the amount of optical distortion of light transmitted through a

windshield **(3)** (applicant's transparent glass member) with unevenness of refractive

power of the windshield, comprising:

a step of picking-up an image of a grid pattern having an array having a bright

portion and a dark portion with a constant pitch and a constant width (see modified

***figure 2** below) by using an image pickup device including a CCD pixel array and*

enabling $4n\pm\alpha$ CCD pixels to correspond to n grids, and n and α are integers greater

than zero, thereby generating α moiré fringes, upon picking-up the image of the grid

pattern on said image pickup device,

The moire image which is detected on the camera results from superimposition

of two brightness distributions with a specific periodicity, in which case the approximate

profiling of sine wave of the moire structure can be recognized on the "grid" of pixels

over the width of a line pair of the sequence which corresponds to a light/dark period

(Page 3, 4th Paragraph);
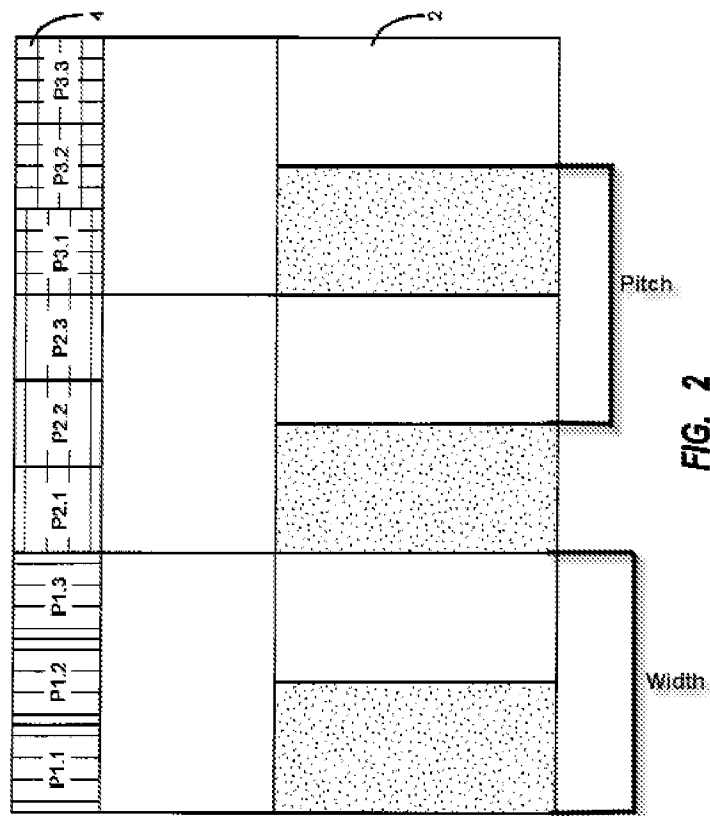
FIG. 2

in the above illustration three pixels correspond to one pair of dark and light

areas. In the above illustration each dark and light pair would produce one moire fringe;

a step of processing, by image processing means, gray image data of the grid

pattern picked-up by said image pickup device via said transparent plate member,

step of processing by the image processing means comprises:

a step of calculating a plurality of types of sine waves that are deviated in phase

at 90° from image data of said moiré fringes,

it is advantageously possible to use the value of the second and third pixels as

the value for the record shifted through 120° and 240° (or -120°). These moire image

strips, offset through 120° (one third of a complete sine wave) and detected by the

pixels of the camera can, after simple conversion, be expressed mathematically as curves that are dependent on a sine function (**Page 3, 5ᵗʰ paragraph**) and,

if the number of pixels associated with a light/dark pair is increased, by a factor of, for example, four (five) or more, this allows an evaluation to be carried out using a phase-shift method shifted in each case by 90° (**Page 3, 8ᵗʰ Paragraph**);

a step of obtaining a phase angle at each pixel based on said plurality of types of sine waves, and

a step of calculating refractive power of the optical distortion based on the difference in phase angles between the pixels,

Variations in the refractive power of the panes, for example a windshield of a motor vehicle, lead to variations in the maxima and minima which occur as a result of the moire phenomenon and can easily be determined as a phase shift (applicants difference in phase angles) in the sine wave; if the distance between the camera and the pane is known, this can be used to determine the angle through which the light that passes through the pane is refracted (**Page 3, Paragraphs 6 & 7**). Thus meeting the limitations of a means for obtaining a phase angle at each pixel based on a plurality of types of sine waves, and calculating the refractive power or angular deviation of an optical distortion, such as a chipped portion;

Pingel fails to explicitly disclose the relationship where α is less than or equal to n/10;

However, this is merely an optimum range of pixels corresponding to grids and requires a mere change of spatial relationship between the CCD and the plate member

to achieve. Thus it would have been well within the abilities of one of ordinary skill in the

art to accomplish this without undue experimentation.

Therefore, it would have been obvious to one of ordinary skill in the art at the

time the invention was made to adjust the position of the CCD so that the number of

pixels to grid patterns corresponds to $4n\pm\alpha$, where n is the number of grids and α is less

than or equal to n/1, since it has been held that where the general conditions of a claim

are disclosed in the prior art, discovering the optimum or working ranges involves only

routine skill in the art. In re Aller, 105 USPQ 233.

3.   Claims 1, 2, 7, & 8 are rejected under 35 U.S.C. 103(a) as being unpatentable

over **Pingel** in view of **Minato** (US PAT 5,216,481) (Minato).

Regarding **Claims 1, 2, 7, & 8** Pingel discloses and shows in **figs. 1 & 2** an

estimating apparatus of the amount of optical distortion of light transmitted through a

windshield (**3**) (applicant's transparent plate member) with unevenness of refractive

power of the transparent plate member, comprising:

*a light source (**1**) (applicant's means for irradiating) for illuminating a grid pattern*

*(**2**) having an array of bright portions and dark portions with constant pitch and a*

*constant width (see modified **figure 2** above);*

*Camera (**4**) (applicant's means for picking-up said grid pattern which includes a*

CCD);

means for inputting a signal from said image pickup device, as gray image data,

another approach to further processing of the lighting pattern, which is preferred

owing to its very good resolution, is to use the moire image that occurs on the pixels of

the camera. The moire image which is detected on the camera results from
superimposition of two brightness distributions with a specific periodicity (**Page 3, 4th**
Paragraph). Thus if the data being recorded by the camera is being processed it has
been inputted, and since brightness distribution is what matters for this method it would
be obvious to use "gray" image data;

4n±α CCD pixels of the CCD pixel array corresponding to n grids (see modified
figure 2 *above),* in the above illustration three pixels correspond to one pair of dark and
light areas. In the above illustration each dark and light pair would produce one moire
fringe;

image processing means comprising:

means for calculating a plurality of types of sine waves that are deviated in phase
at 90° from image data of said moiré fringes,

it is advantageously possible to use the value of the second and third pixels as
the value for the record shifted through 120° and 240° (or -120°). These moire image
strips, offset through 120° (one third of a complete sine wave) and detected by the
pixels of the camera can, after simple conversion, be expressed mathematically as
curves that are dependent on a sine function (**Page 3, 5th Paragraph**) and,

if the number of pixels associated with a light/dark pair is increased, by a factor
of, for example, four (five) or more, this allows an evaluation to be carried out using a
phase-shift method shifted in each case by 90° (**Page 3, 8th Paragraph**);

means for obtaining a phase angle at each pixel based on said plurality of types
of sine waves, and

means for calculating refractive power of the optical distortion based on the difference in phase angles between the pixels,

Variations in the refractive power of the panes, for example a windshield of a motor vehicle, lead to variations in the maxima and minima which occur as a result of the moire phenomenon and can easily be determined as a phase shift (applicants difference in phase angles) in the sine wave; if the distance between the camera and the pane is known, this can be used to determine the angle through which the light that passes through the pane is refracted (**Page 3, Paragraphs 6 & 7**). Thus meeting the limitations of a means for obtaining a phase angle at each pixel based on a plurality of types of sine waves, and calculating the refractive power or angular deviation of an optical distortion, such as a chipped portion;

Pingel fails to disclose a means for supporting and conveying said transparent plate member in an optical line ranging from said grid pattern to said image pickup device and the relationship where α is less than or equal to n/10;

However, Minato teaches and shows in **fig. 2** an apparatus for inspecting transparent objects for defects, comprising:

a conveyor (**3**) (applicant's means for supporting and conveying) for transporting to an inspecting position a transparent glass;

It would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the invention of Pingel with the conveyor for advantages such as the automation of inspection to ensure consistent distance between the camera and glass, and to improve throughput of the inspection process.

Pingel as modified by Minato still fails to explicitly disclose the relationship where α is less than or equal to n/10;

However, this is merely an optimum range of pixels corresponding to grids and requires a mere change of spatial relationship between the CCD and the plate member to achieve. Thus it would have been well within the abilities of one of ordinary skill in the art to accomplish this without undue experimentation.

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to adjust the position of the CCD so that the number of pixels to grid patterns corresponds to $4n\pm\alpha$, where n is the number of grids and α is less than or equal to n/1, since it has been held that where the general conditions of a claim are disclosed in the prior art, discovering the optimum or working ranges involves only routine skill in the art. In re Aller, 105 USPQ 233.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to JONATHON D. COOK whose telephone number is (571)270-1323. The examiner can normally be reached on Mon-Fri 9:00am to 5:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Tarifur Chowdhury can be reached on (571)272-2287. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the

Patent Application Information Retrieval (PAIR) system. Status information for

published applications may be obtained from either Private PAIR or Public PAIR.

Status information for unpublished applications is available through Private PAIR only.

For more information about the PAIR system, see http://pair-direct.uspto.gov. Should

you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a

USPTO Customer Service Representative or access to the automated information

system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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AU:2886
June 30th, 2008

/TARIFUR R CHOWDHURY/
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